Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/803,183	CHEN ET AL.	
Examiner	Art Unit	
Hien N. Nguyen	2824	

	SEARCHED					
Class	Subclass	Date	Examiner			
365	185.17	7/25/2005	HN 1			
365	185.29					
365	185.33					
257	314					
257	315					
257	316					
257	317	V	1			

Subclass	Date	Examiner
185.17	10/20/05	HN
185.29		
314	4	\rightarrow
10.1		,
	185.17 185.29	185.17 10/20/05

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST	7/25/2005	HN		